

## **AWARD WINNING PERFORMANCE**

High performance devices call for high performance test and burn-in solutions and require participation by the entire test ecosystem including contactors, sockets, the DUT board, along with the environment that testing takes place in and the methodology applied. This session provides insight to each step beginning with the development of a statistical model to identify the optimized bandwidth for spring probes. Next up is a look at environmental factors that can readily impact socket performance and thus indirectly test yield. The third presentation verifies test methodology to troubleshoot a device that is having issues in a very high performance test contactor to determine the cause of the issues and affect changes to prevent them from reoccurring. Lastly, we'll hear about the unique challenges to create an optimized test methodology for 25 to 40 GHz RF amplifiers, mixers, and down converters in LFCSP (QFN) and WLCSP packages, considering connectivity issues between DUT board and sockets.



This Paper

### **Design of Experiments Using Spring Probe Parameters for Optimized Socket Bandwidth**

Mike Fedde, Ila Pal—Ironwood Electronics, Inc.

### **Socket Performance vs. Environmental Conditions**

Gert Hohenwarter—GateWave Northern, Inc.

### **Troubleshooting Test Oscillation Problems**

Jeff Sherry—Johnstech International Corporation

### **Optimization of Package, Socket and PC Board for 25 to 40GHz RF Devices**

Carol McCuen, Phil Warwick—R&D Circuits, Inc.

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# Design of Experiments Using Spring Probe Parameters for Optimized Socket Bandwidth

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2013 BiTS Workshop  
March 3 - 6, 2013



## Content

- Problem definition
- Seven principles of interconnect design for optimized insertion loss
- Key input variables and output variable
- Design of experiments
- Experimental results
- Analysis of results
- Optimized insertion loss model
- Confirmation run to verify model
- Conclusions

## Problem Definition

- There is no established relation between critical spring probe parameters and their influence on signal integrity.
- There is no baseline reference and a starting point for spring probe design which is an everyday need due to emerging new application requirements.

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## Seven principles of interconnect design for optimized insertion loss

Signal Integrity experts say:

1. Match characteristic impedance of socket to 50 Ohms
2. Keep the impedance constant through socket
3. Optimize (minimize) pad stack up capacitance
4. Keep socket short
5. Dielectric loss of socket not critical
6. Conductor loss of socket not critical
7. Contact resistance of socket not critical

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## Key input variables and output variable

- Input variables
  - Spring pin length (1mm to 4mm)
  - Spring pin diameter (0.25mm to 0.35mm)
  - Ground pattern
    - C1 (G-S-G)  
G
    - C2 G-S-G  
G
- Output variable
  - Bandwidth (GHz) at -1dB Insertion loss

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## Design of experiments

Study Type Factorial  
Runs 8  
Initial Design 2 Level Factorial  
Blocks No Blocks  
Center Points 0  
Design Model 3FI

Name	Units	Type	Low Actual	High Actual	Low Coded	High Coded	Mean	Std. Dev.
Diameter	mm	Numeric	0.25	0.35	-1	1	0.3	0.05
Length	mm	Numeric	1	4	-1	1	2.5	1.5
Ground		Categoric	C1	C2			Levels:	2

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## Design of experiments

Standard Order	Run Order	Block	Diameter (mm)	Length (mm)	Ground pattern	Bandwidth (GHz)
7	1	Block 1	0.25	4	C2	
4	2	Block 1	0.35	4	C1	
3	3	Block 1	0.25	4	C1	
8	4	Block 1	0.35	4	C2	
5	5	Block 1	0.25	1	C2	
6	6	Block 1	0.35	1	C2	
2	7	Block 1	0.35	1	C1	
1	8	Block 1	0.25	1	C1	

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## Experimental results

Standard Order	Run Order	Block	Diameter (mm)	Length (mm)	Ground pattern	Bandwidth (GHz)
7	1	Block 1	0.25	4	C2	14
4	2	Block 1	0.35	4	C1	5.6
3	3	Block 1	0.25	4	C1	13.9
8	4	Block 1	0.35	4	C2	4
5	5	Block 1	0.25	1	C2	31
6	6	Block 1	0.35	1	C2	14.8
2	7	Block 1	0.35	1	C1	19
1	8	Block 1	0.25	1	C1	33

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## Analysis of results

Design-Expert® Software  
Bandwidth

Shapiro-Wilk test  
W-value = 0.981  
p-value = 0.942

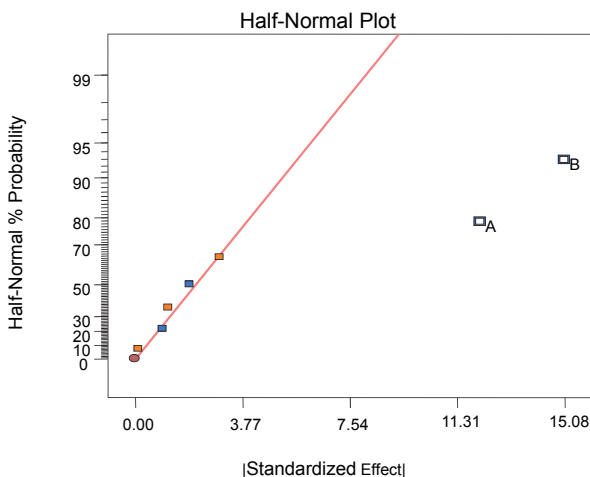
A: Diameter

B: Length

C: Ground

Positive Effects

Negative Effects

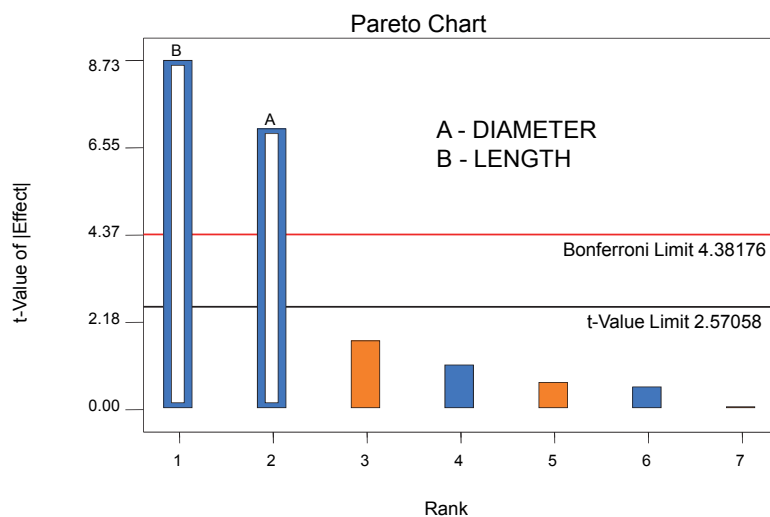


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## Analysis of results



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## Analysis of results

Response	Bandwidth					
ANOVA for selected factorial model						
Source	Sum of Squares	df	Mean Square	F Value	p-value, Prob > F	
Model	748.5425	2	374.27125	62.78402181	0.0003	significant
A-Diameter	294.03125	1	294.03125	49.3237576	0.0009	
B-Length	454.51125	1	454.51125	76.24428601	0.0003	
Residual	29.80625	5	5.96125			
Cor Total	778.34875	7				

The Model F-value of 62.78 implies the model is significant. There is only a 0.03% chance that a "Model F-Value" this large could occur due to noise.

Values of "Prob > F" less than 0.0500 indicate model terms are significant. In this case A, B are significant model terms.

Values greater than 0.1000 indicate the model terms are not significant.

Std. Dev.	2.4415671	R-Squared	0.961705791
Mean	16.9125	Adj R-Squared	0.946388107

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## Optimized insertion loss model

$$\begin{aligned} \text{Bandwidth} = & +65.85000 \\ & -121.25000 * \text{Diameter} \\ & -5.02500 * \text{Length} \end{aligned}$$

**Model valid within the following limits**

**Diameter: 0.25mm to 0.35mm**

**Length: 1mm to 4mm**

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## Analysis of results

Design-Expert® Software

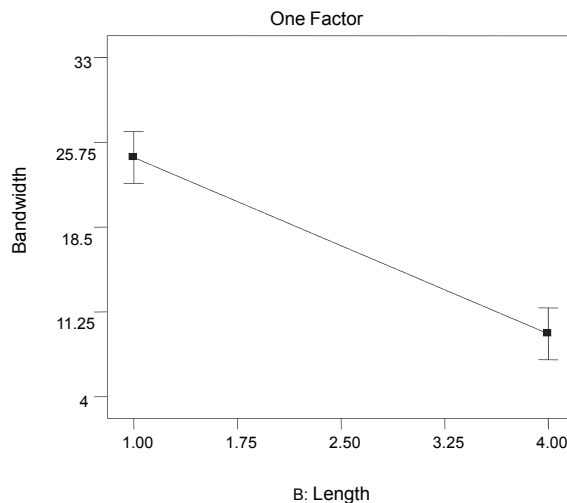
Bandwidth

X1 = B: Length

Actual Factors

A: Diameter = 0.30

C: Ground = C1



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## Analysis of results

Design-Expert® Software

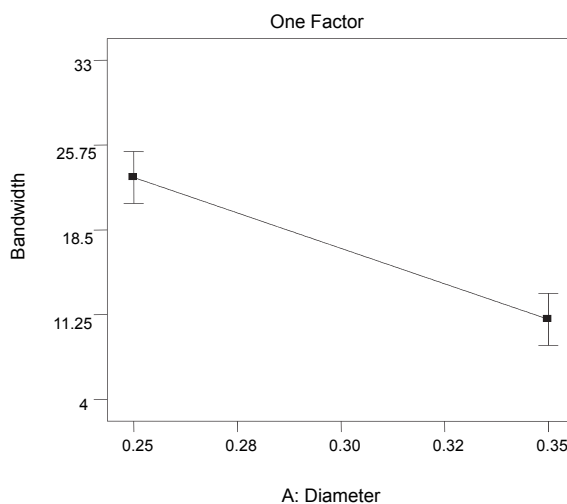
Bandwidth

X1 = A: Diameter

Actual Factors

B: Length = 2.50

C: Ground = C1



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## Optimization of results

To maximize Bandwidth:

5 Solutions found						
Number	Diameter	Length	Ground*	Bandwidth	Desirability	
1	0.25	1	C2	30.51248841	0.914223738	Selected
2	0.25	1	C1	30.51248775	0.914223716	
3	0.25	1.03	C2	30.36742561	0.909221573	
4	0.25	1.03	C1	30.34746318	0.908533213	
5	0.25	1.18	C2	29.6219383	0.883515114	
*Has no effect on optimization results.						

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## Optimization of results

Design-Expert® Software

Bandwidth

● Design Points

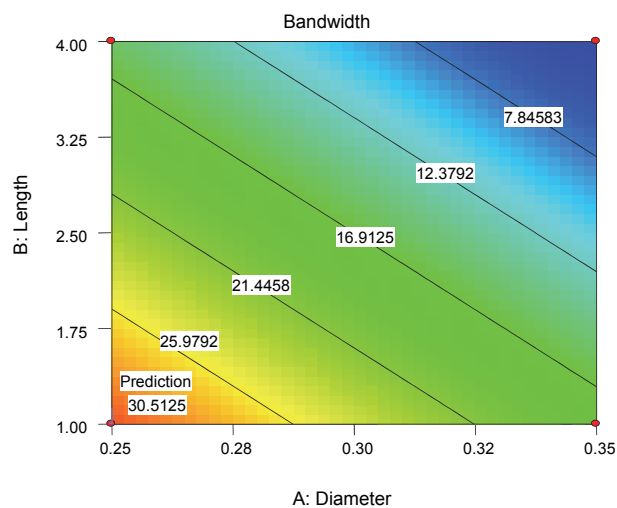
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X1 = A: Diameter

X2 = B: Length

Actual Factor

C: Ground = C2

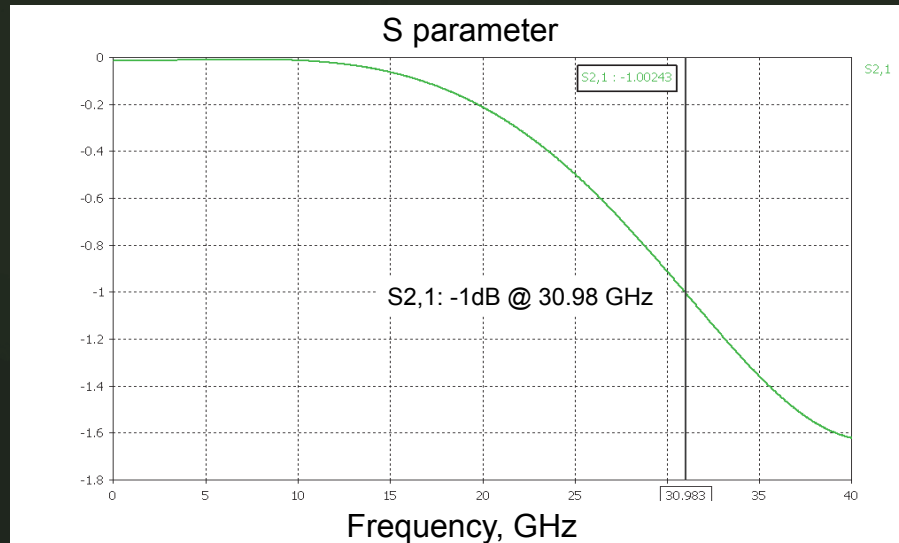


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## Confirmation run to verify model



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## Optimization of results

To maximize Bandwidth and Length:

9 Solutions found						
Number	Diameter	Length	Ground*	Bandwidth	Desirability	
1	0.25	3.64	C1	17.25805757	0.63400549	Selected
2	0.25	3.64	C2	17.25776855	0.634005466	
3	0.25	3.65	C2	17.19991881	0.63399974	
4	0.25	3.62	C1	17.34746791	0.633989528	
5	0.25	3.66	C1	17.13879092	0.633979894	
6	0.25	3.66	C2	17.13074513	0.633977077	
7	0.25	3.61	C1	17.41399089	0.633960073	
8	0.25	3.75	C2	16.70416448	0.633454994	
9	0.25	3.1	C2	19.96789457	0.620599198	
*Has no effect on optimization results.						

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## Optimization of results

Design-Expert® Software

Bandwidth

● Design Points

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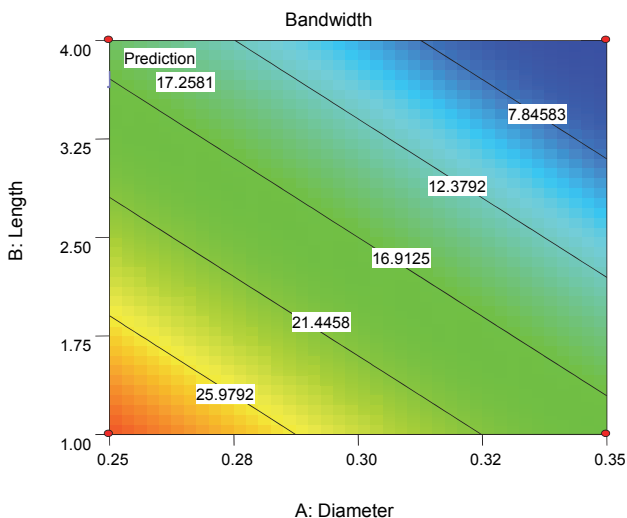
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X1 = A: Diameter

X2 = B: Length

Actual Factor

C: Ground = C1

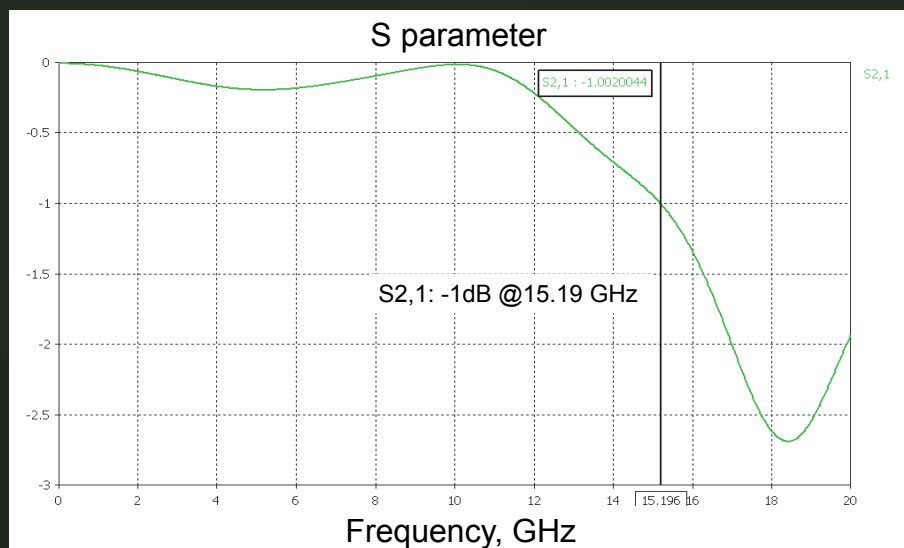


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## Confirmation run to verify model



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## Conclusions

- Key input variables of spring probe and output variable are identified
- A set of experiments were designed using Design Expert Statistical Software
- Experiments were conducted and results were analyzed using Design Expert Statistical Software
- A statistical model was developed that relates spring probe parameters to optimized signal bandwidth.
- A confirmation experiment was performed to verify the validity of model.

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